

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) FIS9-2001-02-US1	Application Number 10/035061		
				Applicant(s) AUSSCHNITT ET AL.			
				Filing Date 12-28-2001	Group Art Unit 2877		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
NY		5,805,290	09-08-98	AUSSCHNITT ET AL.			10/035061 12/28/01
NY		6,091,486	07-18-00	KIRK			
es		5,300,786	04-05-94	BRUNNER ET AL.			
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation
							YES
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
NY		SPIE 3697 - "Application of blazed gratings for determination of equivalent primary azimuthal aberrations" - Kirk and Progler - Proceedings SPIE, Vol. 3679, pp. 70 - 76, Date of Publication 1999, USA					
		SPIE 4000 - "Impact of high order aberrations on the performance of the aberration monitor" - Dirksen et al. - Proceedings SPIE, Vol. 4000, pp. 9 - 17, Date of Publication 2000, USA					
		SPIE 4000 - "In-situ measurement of lens aberrations" - Farrar et al. - Proceedings SPIE, Vol. 4000, pp. 18 - 29, Date of Publication 2000, USA					
ND							
EXAMINER <i>Michael Stach</i>		DATE CONSIDERED 11-15-04 225-04					
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